



PATENT

IN THE UNITED STATES

PATENT AND TRADEMARK OFFICE

APPLICANT(S): Stephen W. Meeks et al.
APPLICATION NO.: 09/347,622
FILING DATE: July 2, 1999
TITLE: System For Simultaneously Measuring Thin Film Layer Thickness,
Reflectivity, Roughness, Surface Profile and Magnetic Pattern
EXAMINER: Tu T. Nguyen
GROUP ART UNIT: 2877
ATTY. DKT. NO.: 20830-04304

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Box Issue Fee, Commissioner For Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date shown below:

Dated: 24 Feb 2004

By: [Signature]
John T. McNelis, Reg. No.: 37,186

BOX ISSUE FEE
COMMISSIONER FOR PATENTS
P.O. BOX 1450
ALEXANDRIA, VA 22313-1450

LETTER TO THE CHIEF DRAFTSPERSON

SIR:

Enclosed are formal drawing containing twenty-five (25) sheets of Figures 1-31 for the above referenced application. The Office Action Summary mailed January 30, 2002 and the Notice of Allowance stated that the drawings as filed were accepted but the Notice of Draftsperson's Patent Drawing Review (attachment to Paper No. 11) indicated that the drawings should be formalized. While the Patent Office did not require these formal drawings, Applicants enclose them as a courtesy.

Respectfully submitted,
Stephen W. Meeks et al.

Dated: February 23, 2004

By: [Signature]
John T. McNelis, Reg. No: 37,186
Fenwick & West LLP
Silicon Valley Center
801 California Street
Mountain View, CA 94041
Tel.: (650) 335-7133
Fax.: (650) 938-5200

20830/04304/DOCS/1412367.1

